## Search Notes



Application/Control No.

10056437

CHO ET AL.

Reexamination

Applicant(s)/Patent Under

Examiner

Lee, Shun

Art Unit

2884

## **SEARCHED**

Class	Subclass	Date	Examiner
250	338.4	6/9/2005	/SL/
257	22	6/9/2005	/SL/
257	194	6/9/2005	/SL/
438	57	6/9/2005	/SL/
Above	UPDATED	2/22/2006	/SL/
Above	UPDATED	6/15/2006	/SL/
Above	UPDATED	6/21/2007	/SL/

## **SEARCH NOTES**

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Search Notes	Date	Examiner
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, IBM_TDB) - See Search History Printout	6/21/2007	/SL/

## **INTERFERENCE SEARCH**

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